

Thin Film Metrology Seminar, 13-14 June 2023, ACPIN AGH, Cracow - Agenda

Tuesday, 13 June (Session i)

10:00 - 17:00	<b>Measurements in research groups</b> <i>(Including a break for lunch)</i>	<i>All</i>
18:00 - 21:00	<b>Social event – dinner</b>	<i>All</i>

Wednesday, 14 June (Session ii)

09:00	<b>Welcome</b>  <i>10 minutes</i>	<i>All</i>
	<b>Introduction into spectroscopic ellipsometry – Complex sample analysis in a wide spectral range from DUV to NIR</b>	<i>Sven Peters, SENTECH</i>
09:55	<b>Coffee break</b>  <i>15 mins</i>	<i>All</i>
10:10	<b>Live Demo</b>  <i>60 minutes</i>	<i>Alexander Treffer, SENTECH</i>
11:10	<b>Ellipsometric measurements of thin oxide films (online)</b>  <i>15 mins + 5 mins discussion</i>	<i>PhD Zbigniew Starowicz, Photovoltaic Laboratory, IMIM PAS</i>
11:30	<b>SiO<sub>x</sub>-TiO<sub>y</sub> thin films as the material platform for the development of integrated optics devices (online)</b>  <i>15 mins + 5 mins discussion</i>	<i>PhD, Hab. Cuma Tyszkiewicz, Silesian University of Technology</i>
11:50	<b>Temperature-dependent spectroscopic ellipsometry of thin polymer films</b>  <i>15 mins + 5 mins discussion</i>	<i>PhD Barbara Hajduk, CMPW PAS</i>
12:10	<b>Lunch</b>  <i>60 minutes</i>	<i>All</i>

**Wednesday, 14 June (Session iii)**

13:10	<b>Metrical, electrical, and chemical information by FTIR ellipsometry in the infrared spectral range</b>  <i>25 mins + 10 mins discussion</i>	<i>Alexander Treffer, SENTECH</i>
13:45	<b>How to recognise and push limits in spectroscopic ellipsometry</b>  <i>25 mins + 10 mins discussion</i>	<i>Sven Peters, SENTECH</i>
14:20	<b>Coffee break</b>	<i>All</i>

**Wednesday, 14 June (Session iv)**

14:40	<b>Spectroscopic ellipsometry and Mueller matrix ellipsometry for the analysis of anisotropic materials and 2D periodic structures (scatterometry)</b>  <i>50 mins + 10 mins discussion</i>	<i>Sven Peters, SENTECH</i>
15:40	<b>Close</b>	<i>All</i>